

Notice of References Cited	Application/Control No. 10/010,779	Applicant(s)/Patent Under Reexamination EISENSTEIN, JONATHAN	
	Examiner Tan Dean D. Nguyen	Art Unit 3629	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0010636	01-2002	Immel, John J.	705/26
*	C	US-2001/0037206	11-2001	Falk et al.	705/1
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	I	US-			
	J	US-			
	K	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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